Statistics for Particle Physics
Lecture 1

Introduction to the Terascale

https://indico.desy.de/event/46666/

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Outline

→ Wednesday 9:00 Quick review of probability

Hypothesis testing

Wednesday 9:45 *p*-values

Confidence intervals / limits

More resources in the University of London course:

https://www.pp.rhul.ac.uk/~cowan/stat_course.html

A quick review of probability

Frequentist (A = outcome of repeatable observation)

$$P(A) = \lim_{n \to \infty} \frac{\text{outcome is in } A}{n}$$

Subjective (A = hypothesis)

$$P(A) = \text{degree of belief that } A \text{ is true}$$

Conditional probability:

$$P(A|B) = \frac{P(A \cap B)}{P(B)}$$

E.g. rolling a die, outcome n = 1,2,...,6:

$$P(n \leq 3 | n \text{ even}) = \frac{P((n \leq 3) \cap n \text{ even})}{P(n \text{ even})} = \frac{1/6}{3/6} = \frac{1}{3}$$

A and B are independent iff:

$$P(A \cap B) = P(A)P(B)$$

I.e. if A, B independent, then

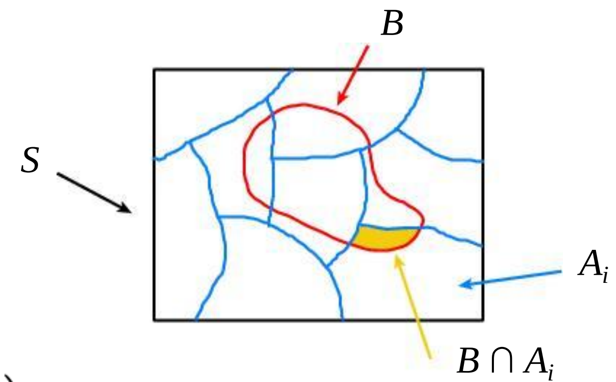
$$P(A|B) = \frac{P(A)P(B)}{P(B)} = P(A)$$

Bayes' theorem

Use definition of conditional probability and $P(A \cap B) = P(B \cap A)$

$$\rightarrow \quad P(A|B) = \frac{P(B|A)P(A)}{P(B)} \qquad \text{(Bayes' theorem)}$$

If set of all outcomes $S = \cup_i A_i$ with A_i disjoint, then law of total probability for $P(B)$ says



$$P(B) = \sum_i P(B \cap A_i) = \sum_i P(B|A_i)P(A_i)$$

so that Bayes' theorem becomes $$P(A|B) = \frac{P(B|A)P(A)}{\sum_i P(B|A_i)P(A_i)}$$

Bayes' theorem holds regardless of how probability is interpreted (frequency, degree of belief...).

Hypothesis, likelihood

Suppose the entire result of an experiment (set of measurements) is a collection of numbers $\boldsymbol{x}$.

A (simple) hypothesis is a rule that assigns a probability to each possible data outcome:

$$P(\mathbf{x}|H) \quad = \quad \text{the likelihood of } H$$

Often we deal with a family of hypotheses labeled by one or more undetermined parameters (a composite hypothesis):

$$P(\mathbf{x}|\boldsymbol{\theta}) = L(\boldsymbol{\theta}) \qquad = \quad \text{the “likelihood function”}$$

Note:

1) For the likelihood we treat the data $\boldsymbol{x}$ as fixed.
2) The likelihood function $L(\boldsymbol{\theta})$ is not a pdf for $\boldsymbol{\theta}$.

Frequentist hypothesis tests

Suppose a measurement produces data $\boldsymbol{x}$; consider a hypothesis H_0 we want to test and alternative H_1

H_0, H_1 specify probability for $\boldsymbol{x}$: $P(\boldsymbol{x}|H_0)$, $P(\boldsymbol{x}|H_1)$

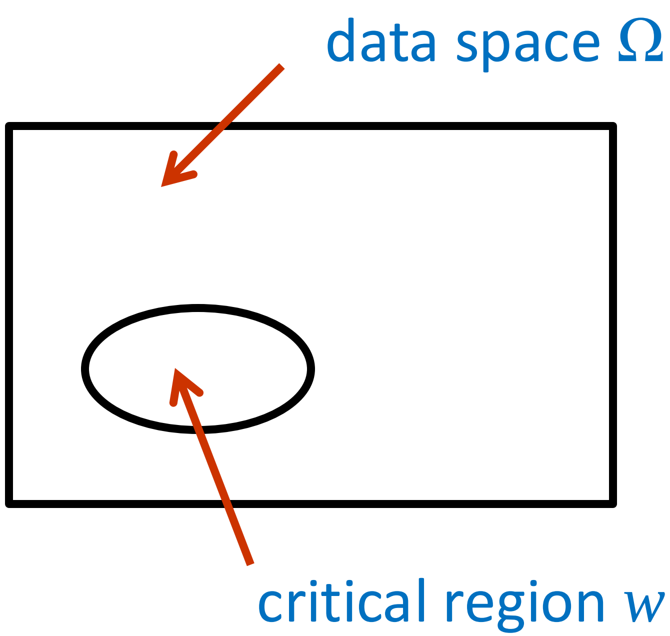
A test of H_0 is defined by specifying a critical region w of the data space such that there is no more than some (small) probability α, assuming H_0 is correct, to observe the data there, i.e.,

$$P(\boldsymbol{x} \in w \mid H_0) \leq \alpha$$

Need inequality if data are discrete.

α is called the size or significance level of the test.

If $\boldsymbol{x}$ is observed in the critical region, reject H_0.

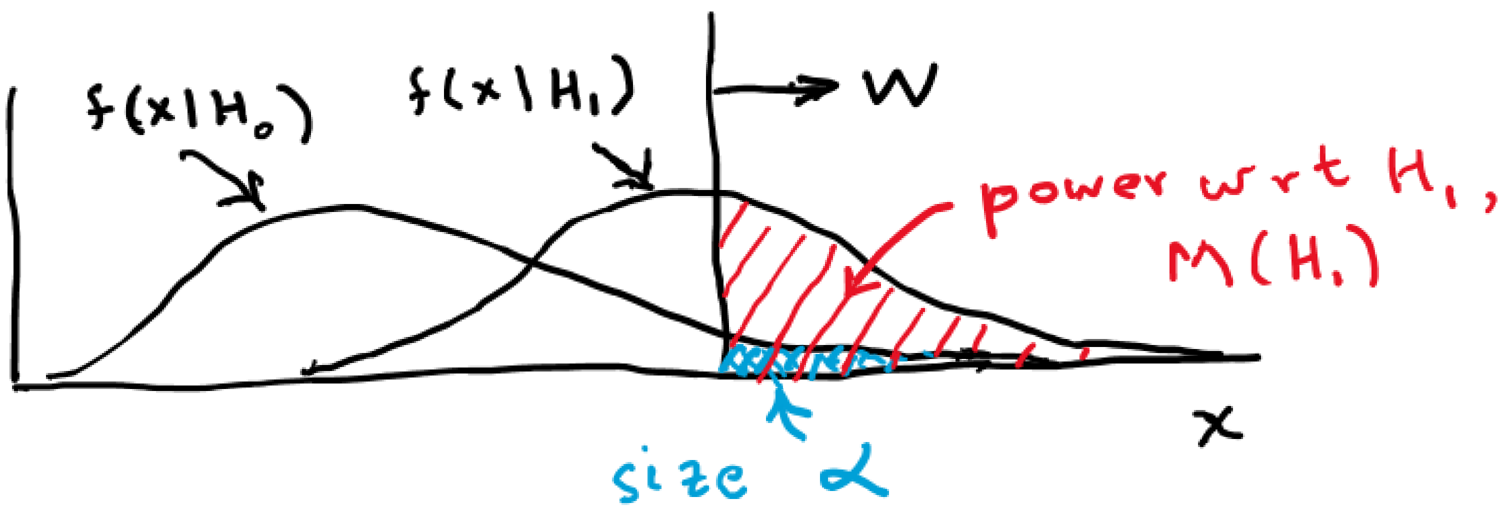


Definition of a test (2)

But in general there are an infinite number of possible critical regions that give the same size α.

Use the alternative hypothesis H_1 to motivate where to place the critical region.

Roughly speaking, place the critical region where there is a low probability (α) to be found if H_0 is true, but high if H_1 is true:



Classification viewed as a statistical test

Suppose events come in two possible types:

s (signal) and b (background)

For each event, test hypothesis that it is background, i.e., H_0 = b.

Carry out test on many events, each is either of type s or b, i.e., here the hypothesis is the "true class label", which varies randomly from event to event, so we can assign to it a frequentist probability.

Select events for which where H_0 is rejected as "candidate events of type s". Equivalent Particle Physics terminology:

background efficiency $$\varepsilon_{\rm b} = \int_W f(\mathbf{x}|H_0)\, d\mathbf{x} = \alpha$$

signal efficiency $$\varepsilon_{\rm s} = \int_W f(\mathbf{x}|H_1)\, d\mathbf{x} = 1 - \beta = \text{power}$$

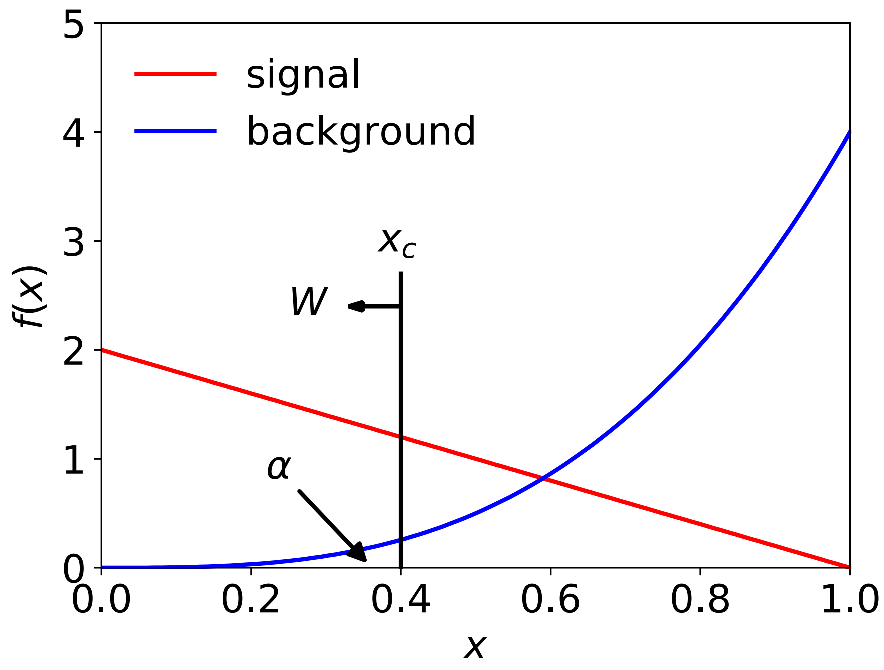
Example of a test for classification

Suppose we can measure for each event a quantity x, where

$$f(x|s) = 2(1-x)$$

$$f(x|b) = 4x^3$$

with $0 \le x \le 1$.



For each event in a mixture of signal (s) and background (b) test

H_0 : event is of type b

using a critical region W of the form: $W = \{x : x \le x_c\}$, where x_c is a constant that we choose to give a test with the desired size α.

Classification example (2)

Suppose we want $\alpha = 10^{-4}$. Require:

$$\alpha = P(x \leq x_{\rm c} | {\rm b}) = \int_0^{x_{\rm c}} f(x|b)\, dx = \left. \frac{4x^4}{4} \right|_0^{x_{\rm c}} = x_{\rm c}^4$$

and therefore $x_{\rm c} = \alpha^{1/4} = 0.1$

For this test (i.e. this critical region W), the power with respect to the signal hypothesis (s) is

$$M = P(x \leq x_{\rm c} | {\rm s}) = \int_0^{x_{\rm c}} f(x|{\rm s})\, dx = 2x_{\rm c} - x_{\rm c}^2 = 0.19$$

Note: the optimal size and power is a separate question that will depend on goals of the subsequent analysis.

Classification example (3)

Suppose that the prior probabilities for an event to be of type s or b are:

$$\pi_{\mathrm{s}} = 0.001$$
$$\pi_{\mathrm{b}} = 0.999$$

The “purity” of the selected signal sample (events where b hypothesis rejected) is found using Bayes’ theorem:

$$P(\mathrm{s}|x \le x_{\mathrm{c}}) = \frac{P(x \le x_{\mathrm{c}}|\mathrm{s})\pi_{\mathrm{s}}}{P(x \le x_{\mathrm{c}}|\mathrm{s})\pi_{\mathrm{s}} + P(x \le x_{\mathrm{c}}|\mathrm{b})\pi_{\mathrm{b}}}$$

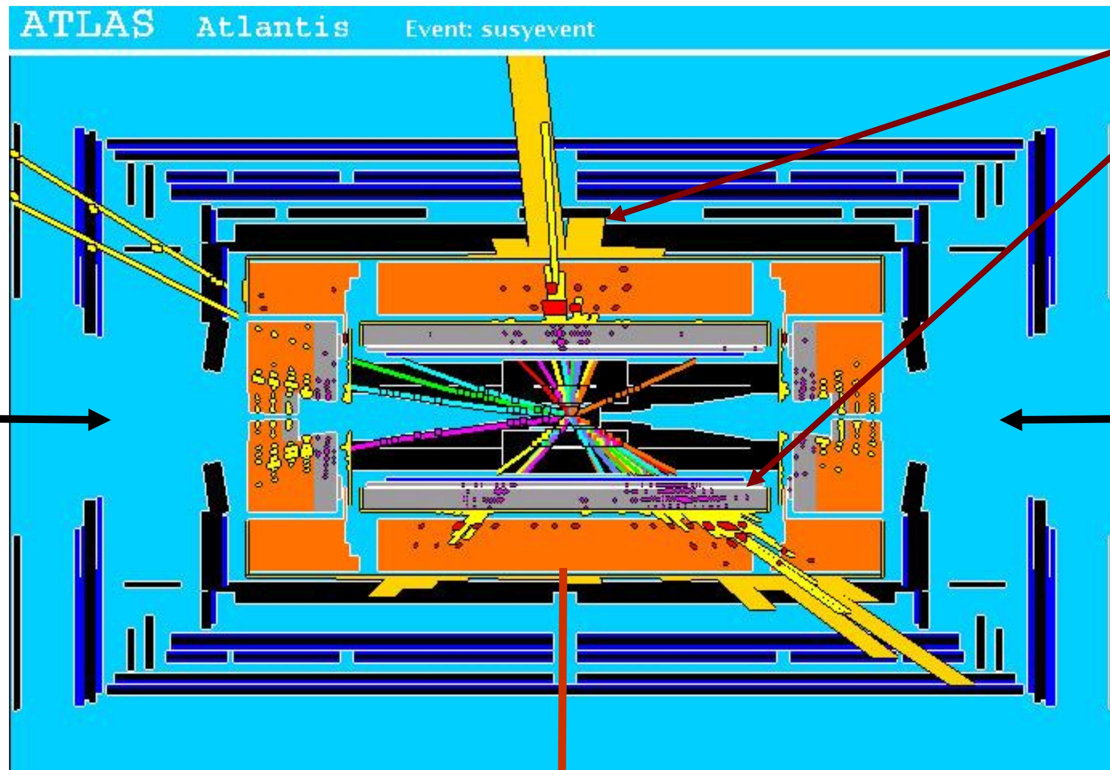
$$= 0.655$$

Particle Physics context for a hypothesis test

A simulated SUSY event ("signal"):

high p_T muons

high p_T jets of hadrons

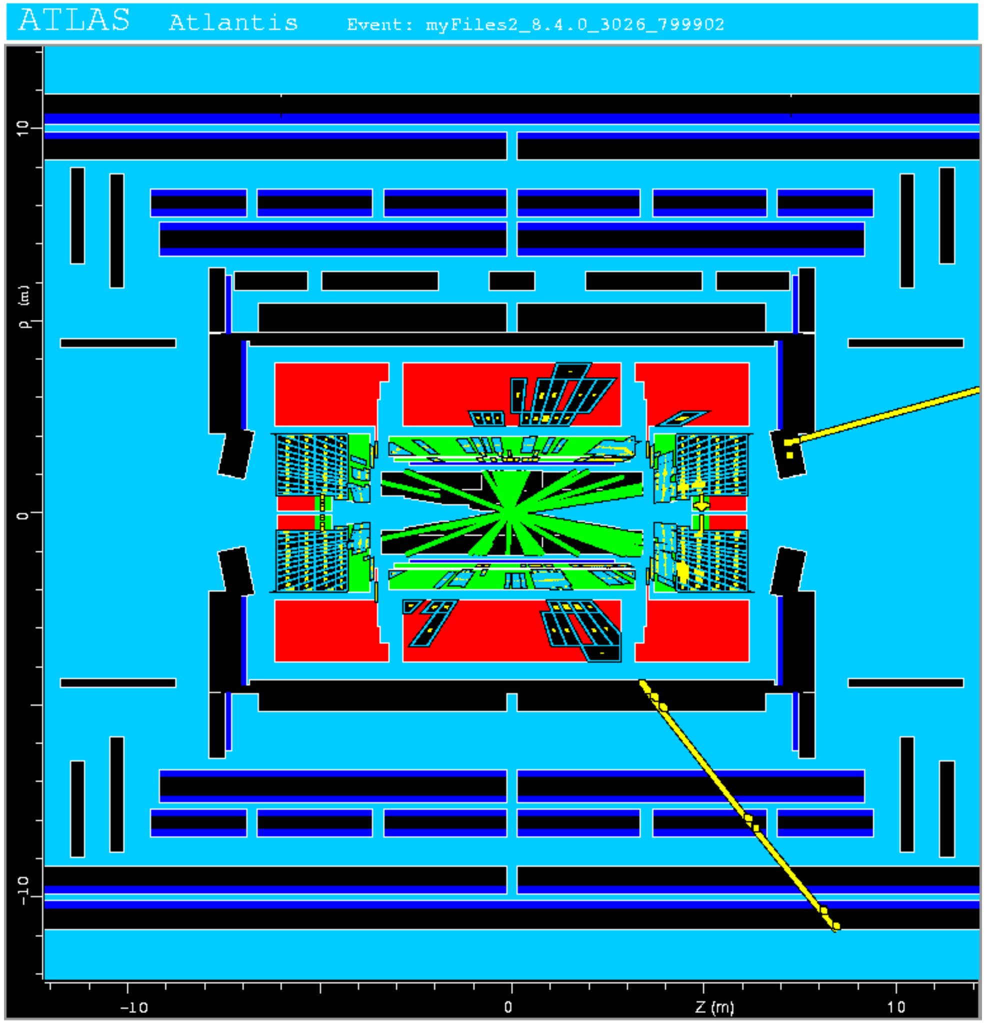


p

p

missing transverse energy

Background events



This event from Standard Model ttbar production also has high p_{T} jets and muons, and some missing transverse energy.

→ can easily mimic a signal event.

Classification of proton-proton collisions

Proton-proton collisions can be considered to come in two classes:

signal (the kind of event we're looking for, $y = 1$)
background (the kind that mimics signal, $y = 0$)

For each collision (event), we measure a collection of features:

x_1 = energy of muon
x_2 = angle between jets
x_3 = total jet energy
x_4 = missing transverse energy
x_5 = invariant mass of muon pair
x_6 = ...

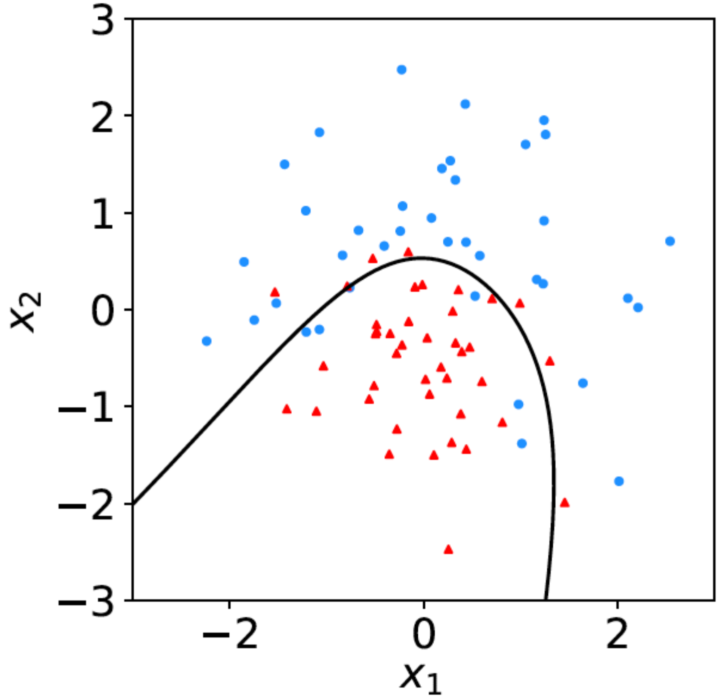
The real events don't come with true class labels, but computer-simulated events do. So we can have a set of simulated events that consist of a feature vector $\boldsymbol{x}$ and true class label y (0 for background, 1 for signal):

$$(\boldsymbol{x}, y)_1, (\boldsymbol{x}, y)_2, ..., (\boldsymbol{x}, y)_N$$

The simulated events are called "training data".

Distributions of the features

If we consider only two features $\boldsymbol{x} = (x_1, x_2)$, we can display the results in a scatter plot (red: $y = 0$, blue: $y = 1$).



For real events, the dots are black (true type is not known).

For each real event test the hypothesis that it is background.

(Related to this: test that a sample of events is *all* background.)

The test's critical region is defined by a "decision boundary" – without knowing the event type, we can classify them by seeing where their measured features lie relative to the boundary.

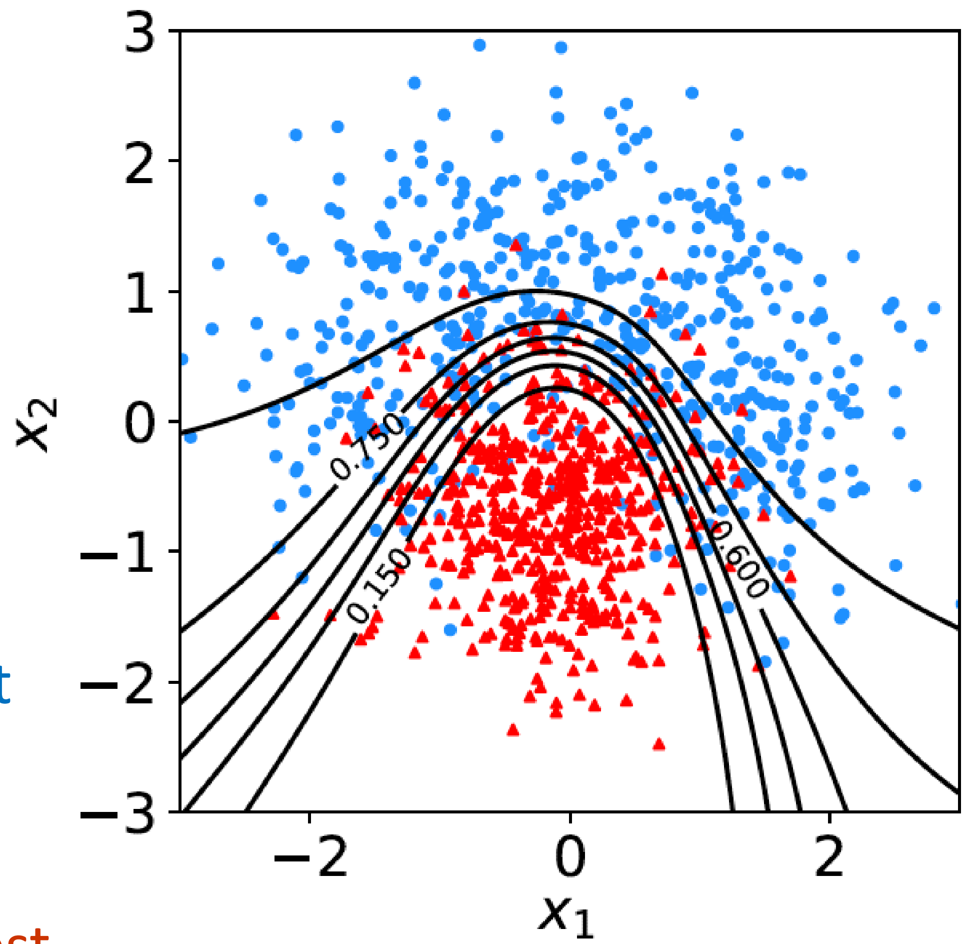
Decision function, test statistic

A surface in an n-dimensional space can be described by

$$t(x_1, \ldots, x_n) = t_c$$

scalar function

constant

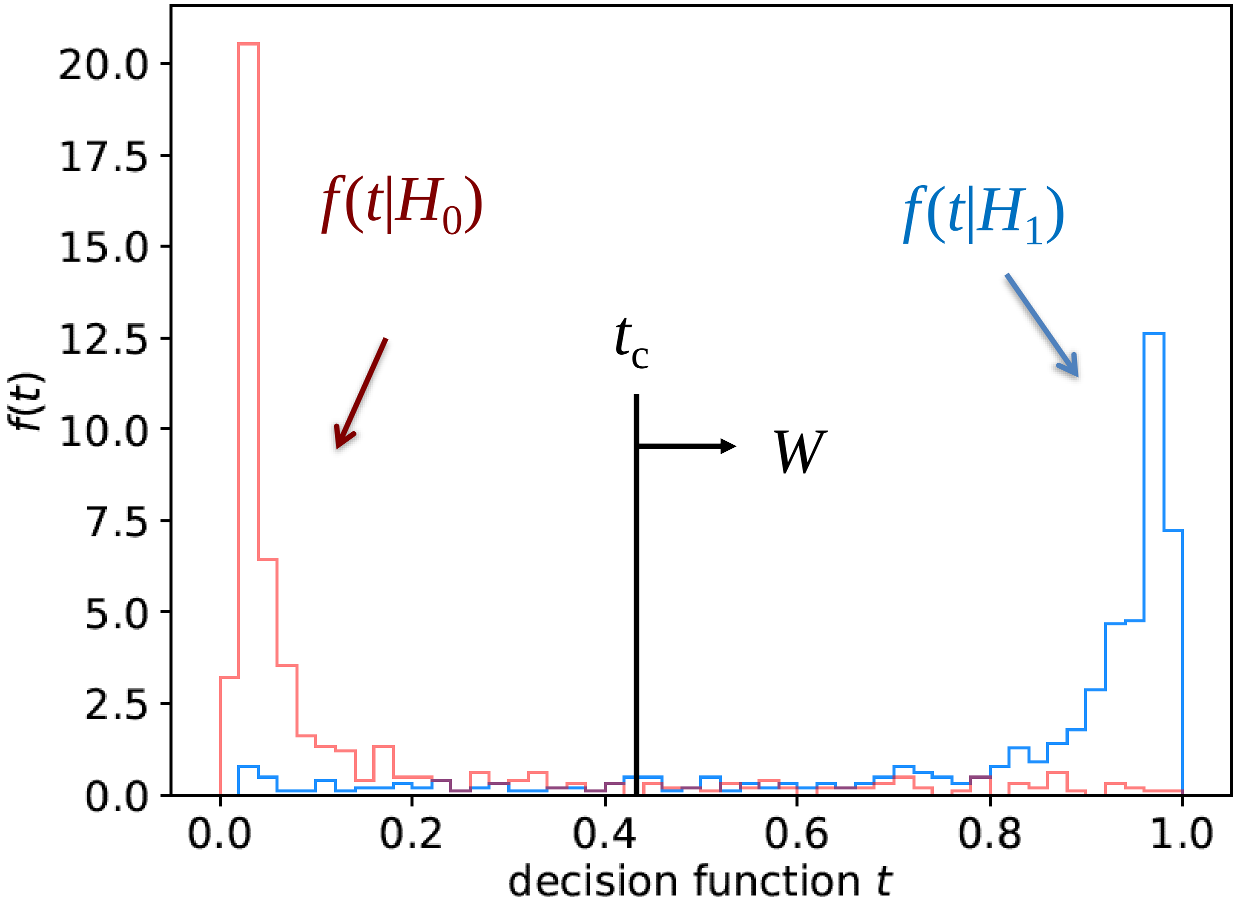


Different values of the constant t_c result in a family of surfaces.

Problem is reduced to finding the best decision function or test statistic $t(\boldsymbol{x})$.

Distribution of $t(\mathbf{x})$

By forming a test statistic $t(\mathbf{x})$, the boundary of the critical region in the n-dimensional $\mathbf{x}$-space is determined by a single single value t_c.

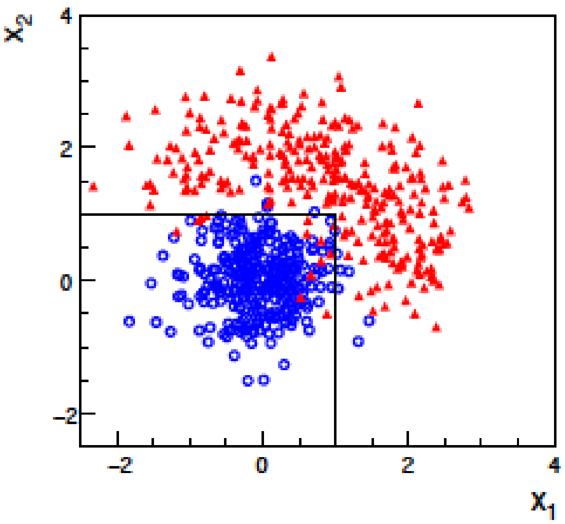


Types of decision boundaries

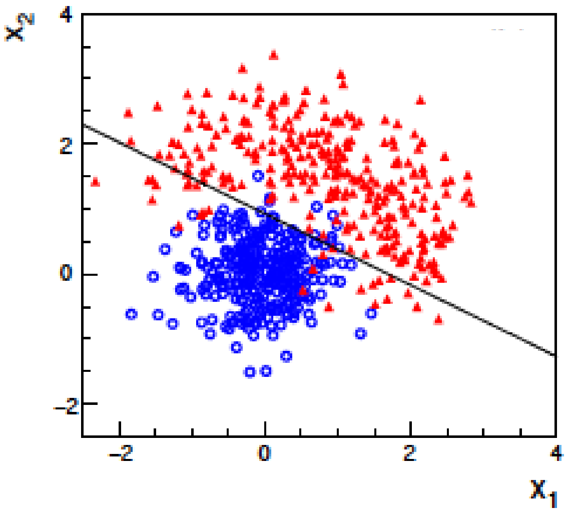
So what is the optimal boundary for the critical region, i.e., what is the optimal test statistic $t(\boldsymbol{x})$?

First find best $t(\boldsymbol{x})$, later address issue of optimal size of test.

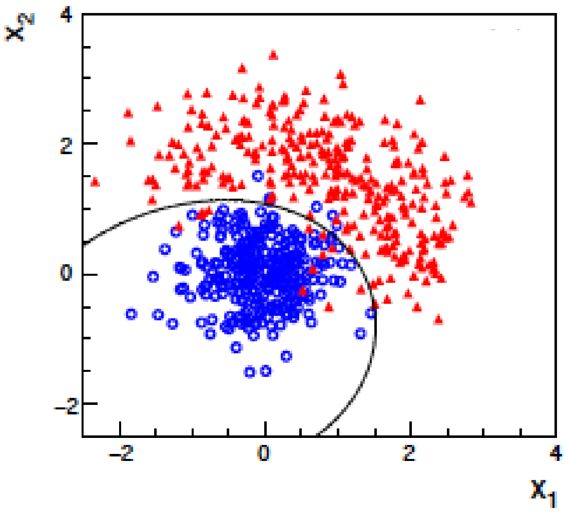
Remember $\boldsymbol{x}$-space can have many dimensions.



"cuts"



linear



non-linear

Test statistic based on likelihood ratio

How can we choose a test's critical region in an 'optimal way', in particular if the data space is multidimensional?

Neyman-Pearson lemma states:

For a test of H_0 of size α, to get the highest power with respect to the alternative H_1 we need for all $\boldsymbol{x}$ in the critical region W

"likelihood ratio (LR)" →

$$\frac{P(\mathbf{x}|H_1)}{P(\mathbf{x}|H_0)} \geq c_\alpha$$

inside W and $\leq c_\alpha$ outside, where c_α is a constant chosen to give a test of the desired size.

Equivalently, optimal scalar test statistic is

$$t(\mathbf{x}) = \frac{P(\mathbf{x}|H_1)}{P(\mathbf{x}|H_0)}$$

N.B. any monotonic function of this is leads to the same test.

Neyman-Pearson doesn't usually help

We usually don't have explicit formulae for the pdfs $f(\boldsymbol{x}|\mathrm{s})$, $f(\boldsymbol{x}|\mathrm{b})$, so for a given $\boldsymbol{x}$ we can't evaluate the likelihood ratio

$$t(\mathbf{x}) = \frac{f(\mathbf{x}|s)}{f(\mathbf{x}|b)}$$

Instead we may have Monte Carlo models for signal and background processes, so we can produce simulated data:

generate $\boldsymbol{x} \sim f(\boldsymbol{x}|\mathrm{s}) \quad \rightarrow \quad \boldsymbol{x}_1, \ldots, \boldsymbol{x}_N$

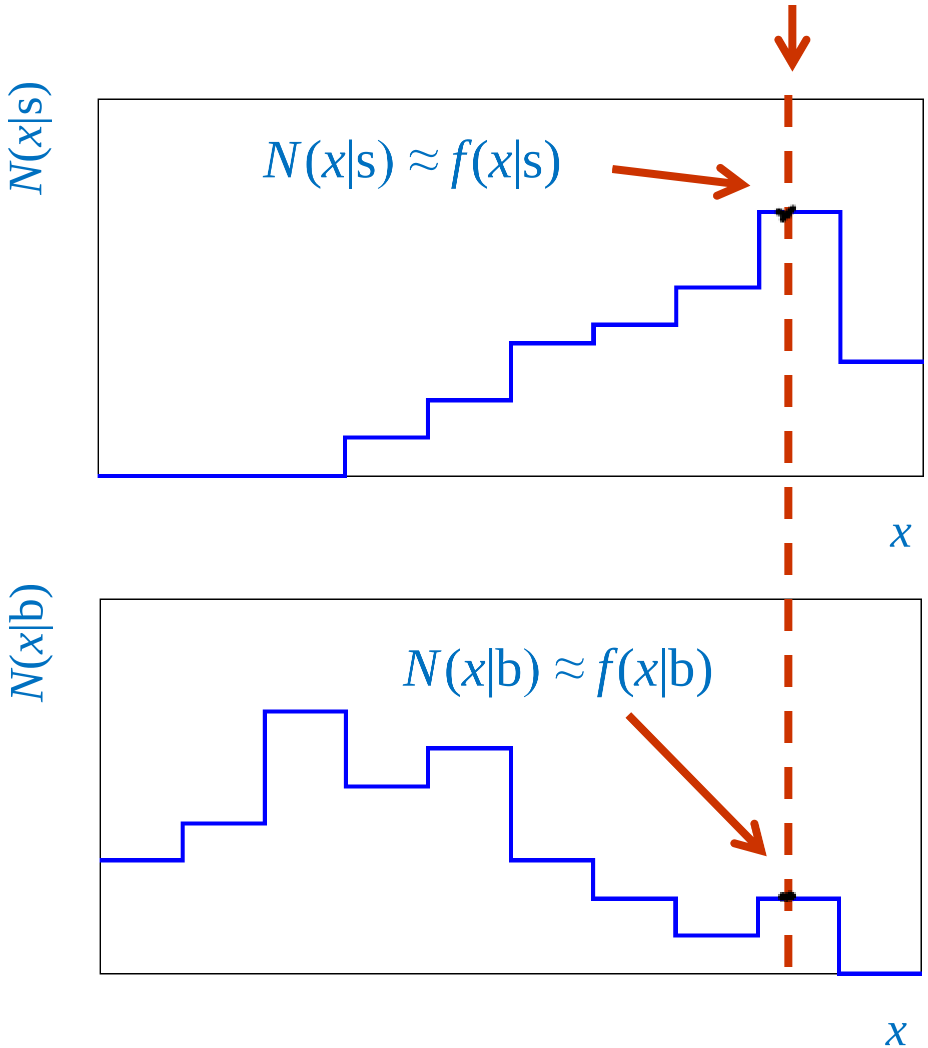
generate $\boldsymbol{x} \sim f(\boldsymbol{x}|\mathrm{b}) \quad \rightarrow \quad \boldsymbol{x}_1, \ldots, \boldsymbol{x}_N$

This gives samples of "training data" with events of known type.

- Use these to construct a statistic that is as close as possible to the optimal likelihood ratio ($\rightarrow$ Machine Learning).

Approximate LR from histograms

Want $t(x) = f(x|s)/f(x|b)$ for x here



One possibility is to generate MC data and construct histograms for both signal and background.

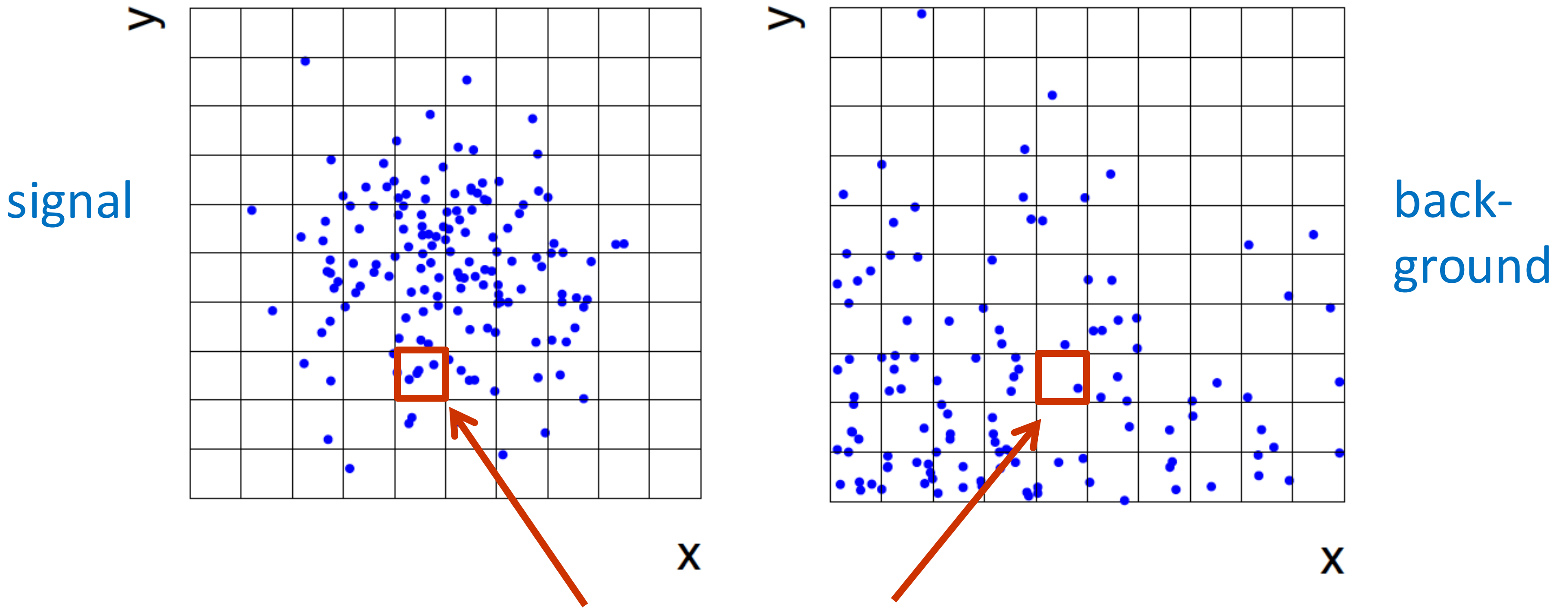
Use (normalized) histogram values to approximate LR:

$$t(x) \approx \frac{N(x|s)}{N(x|b)}$$

Can work well for single variable.

Approximate LR from 2D-histograms

Suppose problem has 2 variables. Try using 2-D histograms:



Approximate pdfs using $N(x,y|\mathrm{s})$, $N(x,y|\mathrm{b})$ in corresponding cells.

But if we want M bins for each variable, then in n-dimensions we have M^n cells; can't generate enough training data to populate.

→ Histogram method usually not usable for $n > 1$ dimension.

Strategies for multivariate analysis

Neyman-Pearson lemma gives optimal answer, but cannot be used directly, because we usually don't have $f(\mathbf{x}|\mathrm{s})$, $f(\mathbf{x}|\mathrm{b})$.

Histogram method with M bins for n variables requires that we estimate M^n parameters (the values of the pdfs in each cell), so this is rarely practical.

A compromise solution is to assume a certain functional form for the test statistic $t(\mathbf{x})$ with fewer parameters; determine them (using MC) to give best separation between signal and background.

Alternatively, try to estimate the probability densities $f(\mathbf{x}|\mathrm{s})$ and $f(\mathbf{x}|\mathrm{b})$ (with something better than histograms) and use the estimated pdfs to construct an approximate likelihood ratio.

Multivariate methods (Machine Learning)

Many new (and some old) methods:

- Fisher discriminant
- (Deep) Neural Networks
- Kernel density methods
- Support Vector Machines
- Decision trees
  - Boosting
  - Bagging

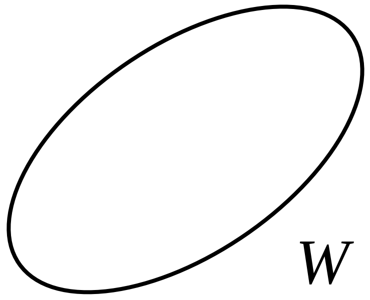
Extra slides

Proof of Neyman-Pearson Lemma

Consider a critical region W and suppose the LR satisfies the criterion of the Neyman-Pearson lemma:

$$P(\mathbf{x}|H_1)/P(\mathbf{x}|H_0) \geq c_\alpha \text{ for all } \mathbf{x} \text{ in } W,$$

$$P(\mathbf{x}|H_1)/P(\mathbf{x}|H_0) \leq c_\alpha \text{ for all } \mathbf{x} \text{ not in } W.$$



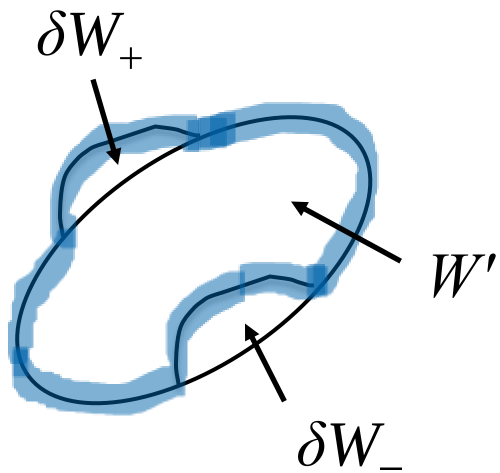
Try to change this into a different critical region W' retaining the same size α, i.e.,

$$P(\mathbf{x} \in W'|H_0) = P(\mathbf{x} \in W|H_0) = \alpha$$

To do so add a part δW_+, but to keep the size α, we need to remove a part δW_-, i.e.,

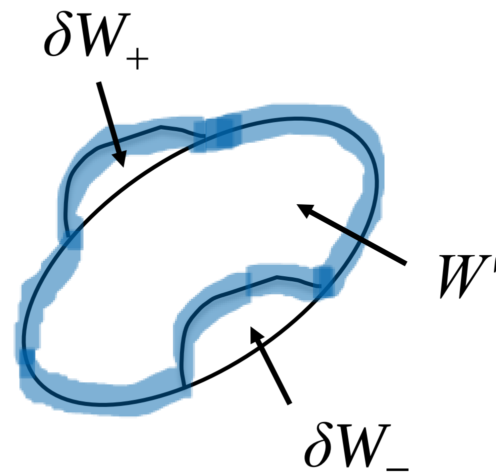
$$W \rightarrow W' = W + \delta W_+ - \delta W_-$$

$$P(\mathbf{x} \in \delta W_+|H_0) = P(\mathbf{x} \in \delta W_-|H_0)$$



Proof of Neyman-Pearson Lemma (2)

But we are supposing the LR is higher for all $\boldsymbol{x}$ in δW_- removed than for the $\boldsymbol{x}$ in δW_+ added, and therefore



$$P(\mathbf{x} \in \delta W_+ | H_1) \leq P(\mathbf{x} \in \delta W_+ | H_0) c_\alpha$$

$$P(\mathbf{x} \in \delta W_- | H_1) \geq P(\mathbf{x} \in \delta W_- | H_0) c_\alpha$$

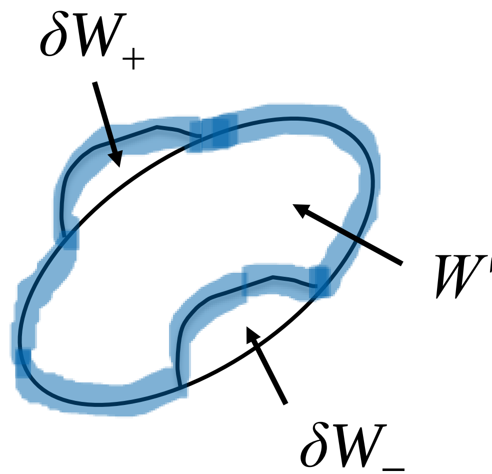
The right-hand sides are equal and therefore

$$P(\mathbf{x} \in \delta W_+ | H_1) \leq P(\mathbf{x} \in \delta W_- | H_1)$$

Proof of Neyman-Pearson Lemma (3)

We have

$$W \cup W' = W \cup \delta W_+ = W' \cup \delta W_-$$



Note W and δW_+ are disjoint, and W' and δW_- are disjoint, so by Kolmogorov's 3rd axiom,

$$P(\mathbf{x} \in W') + P(\mathbf{x} \in \delta W_-) = P(\mathbf{x} \in W) + P(\mathbf{x} \in \delta W_+)$$

Therefore

$$P(\mathbf{x} \in W'|H_1) = P(\mathbf{x} \in W|H_1) + \underbrace{P(\mathbf{x} \in \delta W_+|H_1) - P(\mathbf{x} \in \delta W_-|H_1)}_{\leq 0}$$

Proof of Neyman-Pearson Lemma (4)

And therefore

$$P(\mathbf{x} \in W' | H_1) \leq P(\mathbf{x} \in W | H_1)$$

i.e. the deformed critical region W' cannot have higher power than the original one that satisfied the LR criterion of the Neyman-Pearson lemma.